Tamkang University Academic Year 111, 2nd Semester Course Syllabus

Course Title	INTRODUCTION OF ELECTRON MICROSCOPY	Instructor	CHIANG, CHENG-TIEN
Course Class	TSAXB4A BACHELOR'S PROGRAM IN ADVANCED MATERIALS SCIENCE, 4A	Details	General CourseSelectiveOne Semester
Relevance to SDGs	SDG4 Quality education		

Departmental Aim of Education

- I. Enrich the fundamental knowledge of advanced material sciences.
- $\ensuremath{\mathbb{I}}$. Emphasize the ability of self-expression.
- Ⅲ. Strengthen the ability to experiment and team spirit.
- IV. Develop an international perspective and international exchanges.

Subject Departmental core competences

- A. Possess a fundamental knowledge of mathematics, physics, chemistry and biology. (ratio:50.00)
- B. Cultivate professional knowledge, experimental skills and the applications of nano, optoelectronic, biomedical and macromolecular materials.(ratio:50.00)

Subject Schoolwide essential virtues

- 1. A global perspective. (ratio:10.00)
- 2. Information literacy. (ratio:10.00)
- 3. A vision for the future. (ratio:5.00)
- 4. Moral integrity. (ratio:5.00)
- 5. Independent thinking. (ratio:30.00)
- 6. A cheerful attitude and healthy lifestyle. (ratio:5.00)
- 7. A spirit of teamwork and dedication. (ratio:30.00)
- 8. A sense of aesthetic appreciation. (ratio:5.00)

	Course roduction		uction of electron micros	scopies and their applications, including their instrumentation.	the basics	
	The	correspo	ndences between the c	ourse's instructional objectives and the	cognitive, affective.	
The correspondences between the course's instructional objectives and the cognitive, affective, and psychomotor objectives. Differentiate the various objective methods among the cognitive, affective and psychomotor domains of the course's instructional objectives.						
I. Cognitive: Emphasis upon the study of various kinds of knowledge in the cognition of the course's veracity, conception, procedures, outcomes, etc. II.Affective: Emphasis upon the study of various kinds of knowledge in the course's appeal, morals, attitude, conviction, values, etc.						
III.P	-	ripulatio		course's physical activity and technical		
No.		Teaching Objectives objective methods				
1	Knowledge o	vledge of electron microscopies Cognitive				
	The	correspond	lences of teaching objectives	: core competences, essential virtues, teaching me	thods, and assessment	
No.	Core Competences		Essential Virtues	Teaching Methods	Assessment	
1	AB		12345678	Lecture, Discussion	Discussion(including classroom and online), Report(including oral and written)	
				Course Schedule		
Week	Date		Cour	rse Contents	Note	
1	112/02/13 ~ 112/02/19	overview, geometric optics, Fermat principle				
2	112/02/20 ~ 112/02/26	mirror, prism, lens				
3	112/02/27 ~ 112/03/05	vector field, gradient, curl, divergence				
4	112/03/06 ~ 112/03/12	Maxwell equations				
5	112/03/13 ~ 112/03/19	wave equation, Huygens-Fresnel principle				
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6	112/03/20 ~ 112/03/26	paraxial wave equation		
7	112/03/27 ~ 112/04/02	focus, plan-apochromat objective		
8	112/04/03 ~ 112/04/09	no class (teaching observation day)		
9	112/04/10 ~ 112/04/16	interference, diffraction, grating, optical microscope		
10	112/04/17 ~ 112/04/23	Midterm Exam Week		
11	112/04/24 ~ 112/04/30	spherical and chromatic aberrations, Abbe number		
12	112/05/01 ~ 112/05/07	optical microscope		
13	112/05/08 ~ 112/05/14	cathod ray, magnetic lens		
14	112/05/15 ~ 112/05/21	electrostatic lens, electron microscope		
15	112/05/22 ~ 112/05/28	Graduate Exam Week		
16	112/05/29 ~ 112/06/04			
17	112/06/05 ~ 112/06/11			
18	112/06/12 ~ 112/06/18			
Re	quirement	general physics		
Tea	ching Facility	Computer, Other (beamer and screen)		
Textbooks and Teaching Materials		Slides of the lecture		
References		Introduction to optics, G. Chartier, ISBN: 978-0-387-27598-7, https://doi.org/10.1007/b106780 Physical principles of electron microscopy - an introduction to TEM, SEM, and AEM, R.F. Egerton, ISBN: 978-3-319-39877-8, https://doi.org/10.1007/978-3-319-39877-8 Transmission electron microscopy - a textbook for materials science, part I. basics, D. B. Williams and C. B. Carter, ISBN: 978-0-387-76501-3, https://doi.org/10.1007/978-0-387-76501-3 Introduction to electrodynamics, D. J. Griffiths, ISBN: 978-1108420419, https://doi.org/10.1017/9781108333511 Scanning probe microscopy - atomic force microscopy and scanning tunneling microscopy, B. Voigtländer, ISBN: 978-3-662-45240-0, https://doi.org/10.1007/978-3-662-45240-0 Surface microscopy with low energy electrons, E. Bauer, ISBN: 978-1-4939-0935-3, https://doi.org/10.1007/978-1-4939-0935-3		

Number of Assignment(s)	(Filled in by assignment instructor only)			
Grading Policy	 Attendance: 40.0 %			
Note	This syllabus may be uploaded at the website of Course Syllabus Management System at http://info.ais.tku.edu.tw/csp or through the link of Course Syllabus Upload posted on the home page of TKU Office of Academic Affairs at http://www.acad.tku.edu.tw/CS/main.php . ** Unauthorized photocopying is illegal. Using original textbooks is advised. It is a crime to improperly photocopy others' publications.			

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